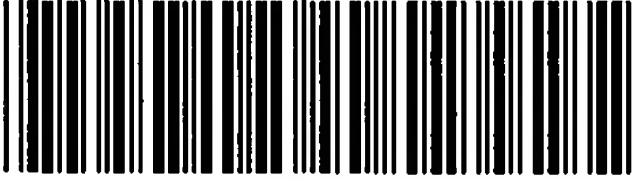


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/635,410	VAN EGMOND ET AL.	
	Examiner	Art Unit	
	Tam M. Nguyen	1764	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
see PGPUb printout		10/30/2006	tn

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
interference searched - see PGPUb printout	10/30/2006	tn